

RoHS

COMPLIANT

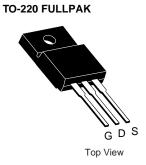
## FQPF6N90C-VB Datasheet

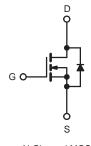
N-Channel 900 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	900	)			
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	1.2			
Q <sub>g</sub> (Max.) (nC)	200				
Q <sub>gs</sub> (nC)	24				
Q <sub>gd</sub> (nC)	110				
Configuration	Single				

#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ( $T_{\mbox{\scriptsize C}}$	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	900	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	I <sub>D</sub>	5		
Continuous Drain Gunent				3.9	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.8	A	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	190	W	
Peak Diode Recovery dV/dt <sup>c</sup>	•		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
Mounting Torque			F	1.1	N · m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50$  V, starting  $T_J = 25$  °C, L = 23 mH,  $R_g = 25 \Omega$ ,  $I_{AS} = 7.8$  A (see fig. 12). c.  $I_{SD} \leq 7.8$  A, dl/dt  $\leq 140$  A/µs,  $V_{DD} \leq 600$  V,  $T_J \leq 150$  °C. d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply

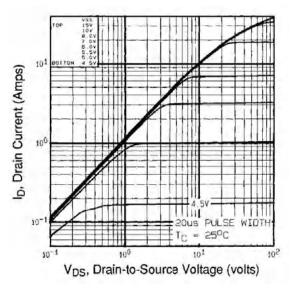
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THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.				
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-		40				
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24		-			°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-		0.65	0.65			
<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static								
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 2	250 µA	900	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	$I_D = 1 \text{ mA}$	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1	= V <sub>GS</sub> , I <sub>D</sub> =		2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 20$		-	-	± 100	nA
		V <sub>DS</sub> =	= 800 V, V <sub>G</sub>	<sub>iS</sub> = 0 V	-	-	100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 640 V	/, V <sub>GS</sub> = 0 \	/, T <sub>J</sub> = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		a = 3.7 A <sup>b</sup>	-	1.2	-	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =	100 V, I <sub>D</sub> =	= 3.7 A <sup>b</sup>	5.6	-	-	S
Dynamic								<b>I</b>
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V	,	-	3100	-	
Output Capacitance	C <sub>oss</sub>	-	$V_{DS} = 25$ V	Ι,	-	800	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	.0 MHz, se	e fig. 5	-	490	-	
Total Gate Charge	Qg				-	-	200	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		A, V <sub>DS</sub> = 400 V, ig. 6 and 13 <sup>b</sup>	-	-	24	nC
Gate-Drain Charge	Q <sub>gd</sub>		300 1	ig. o and 15	-	-	110	
Turn-On Delay Time	t <sub>d(on)</sub>				-	19	-	
Rise Time	tr	$ \begin{array}{c c} V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A}, \\ R_{g} = 6.2 \Omega, R_{D} = 52 \Omega \\ \text{see fig. 10^{b}} \\ \end{array} \begin{array}{c c} - & 38 \\ - & 120 \\ \end{array} $		-	ns			
Turn-Off Delay Time	t <sub>d(off)</sub>			-				
Fall Time	t <sub>f</sub>		see lig. To		-	39	-	1
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact - 5.0 - 13 -		-	- nH			
Internal Source Inductance	Ls			-				
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym	bol		-	-	5.0	Δ
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral revers p - n junction			-	-	21	A
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C	, I <sub>S</sub> = 3.8 A	$V_{GS} = 0 V^{b}$	-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T.=	25 °C, I <sub>F</sub> =	3.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	dl	/dt = 100 A	∕µs <sup>b</sup>	-	3.8	5.7	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tur	n-on time	is negligible (turn	-on is do	minated b	$_{\rm S}$ and	L <sub>D</sub> )

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



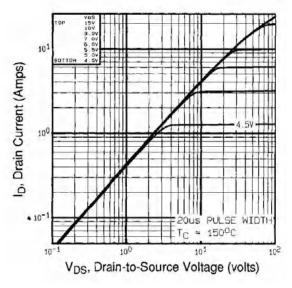


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

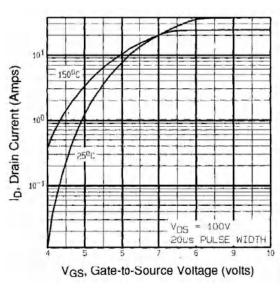
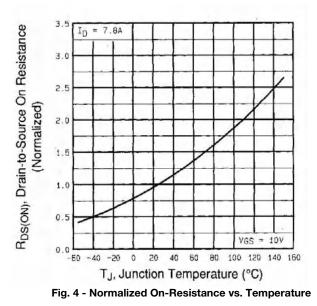


Fig. 3 - Typical Transfer Characteristics





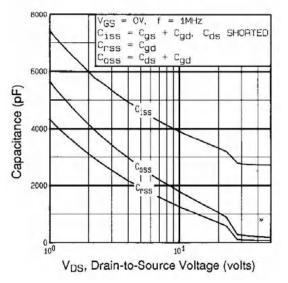


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 7 - Typical Source-Drain Diode Forward Voltage

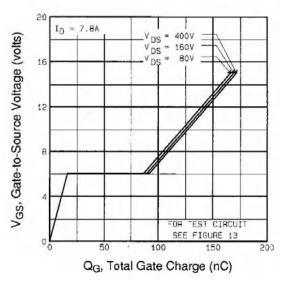
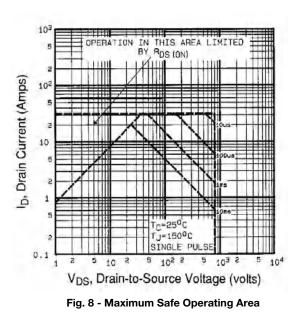


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





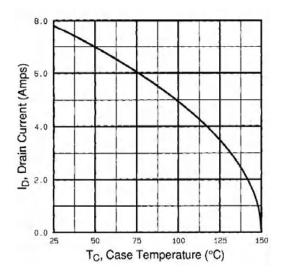


Fig. 9 - Maximum Drain Current vs. Case Temperature

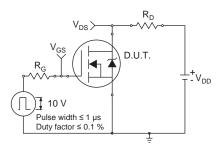


Fig. 10a - Switching Time Test Circuit

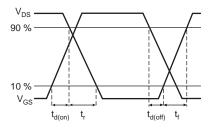


Fig. 10b - Switching Time Waveforms

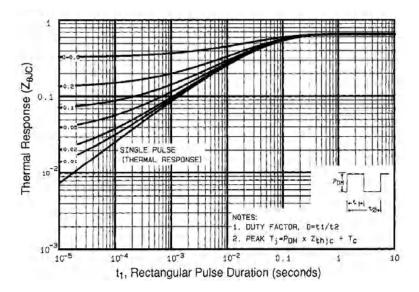


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



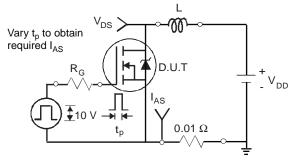


Fig. 12a - Unclamped Inductive Test Circuit

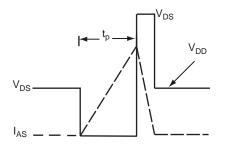


Fig. 12b - Unclamped Inductive Waveforms



Fig. 12c - Maximum Avalanche Energy vs. Drain Current

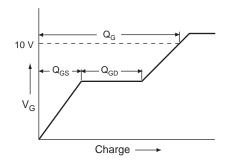


Fig. 13a - Basic Gate Charge Waveform

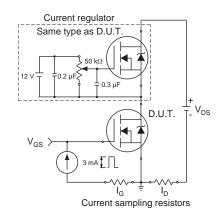
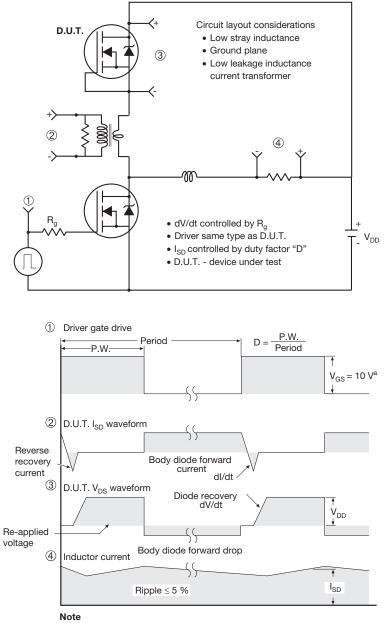


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

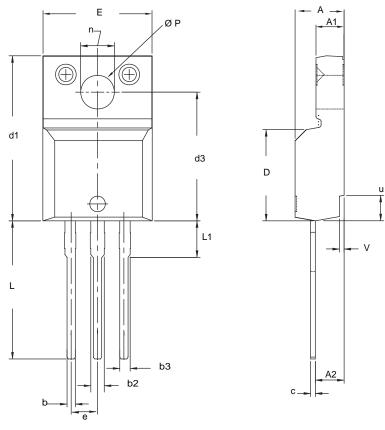


a.  $V_{GS} = 5$  V for logic level devices

Fig. 14 - For N-Channel



#### **TO-220 FULLPAK (HIGH VOLTAGE)**



MIN.           4.570           2.570           2.510           0.622           1.229           1.229           0.440           8.650           15.88	MAX.           4.830           2.830           2.850           0.890           1.400           0.629           9.800	MIN.           0.180           0.101           0.099           0.024           0.048           0.048           0.017           0.341	MAX. 0.190 0.111 0.112 0.035 0.055 0.055 0.055 0.025 0.386
2.570 2.510 0.622 1.229 1.229 0.440 8.650	2.830 2.850 0.890 1.400 1.400 0.629 9.800	0.101 0.099 0.024 0.048 0.048 0.048	0.111 0.112 0.035 0.055 0.055 0.055 0.025
2.510 0.622 1.229 1.229 0.440 8.650	2.850 0.890 1.400 1.400 0.629 9.800	0.099 0.024 0.048 0.048 0.017	0.112 0.035 0.055 0.055 0.025
0.622 1.229 1.229 0.440 8.650	0.890 1.400 1.400 0.629 9.800	0.024 0.048 0.048 0.017	0.035 0.055 0.055 0.025
1.229         1.229         0.440         8.650	1.400 1.400 0.629 9.800	0.048 0.048 0.017	0.055 0.055 0.025
1.229 0.440 8.650	1.400 0.629 9.800	0.048 0.017	0.055 0.025
0.440 8.650	0.629 9.800	0.017	0.025
8.650	9.800		
		0.341	0.386
15.88	16 100		0.000
	16.120	0.622	0.635
12.300	12.920	0.484	0.509
10.360	10.630	0.408	0.419
2.54	4 BSC	0.100	BSC
13.200	13.730	0.520	0.541
3.100	3.500	0.122	0.138
6.050	6.150	0.238	0.242
3.050	3.450	0.120	0.136
2.400	2.500	0.094	0.098
0.400	0.500	0.016	0.020
	10.360 2.54 13.200 3.100 6.050 3.050 2.400	10.360         10.630           2.54 BSC         13.730           3.100         3.500           6.050         6.150           3.050         3.450           2.400         2.500	10.360         10.630         0.408           2.54 BSC         0.100           13.200         13.730         0.520           3.100         3.500         0.122           6.050         6.150         0.238           3.050         3.450         0.120           2.400         2.500         0.094

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet  $C_{pk} > 1.33$ . 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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